



11-10-03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Docket: BUR920020113US1

Filing Date: 07/02/03  
Application No.: 10/604230  
Applicant: Conti et al.

Examiner: Unassigned  
Group Art Unit: Unassigned  
Confirmation No.: unkNowN

Title: **APPLYING PARAMETRIC TEST PATTERNS FOR HIGH PIN COUNT ASICs ON  
LOW PIN COUNT TESTERS.**

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 CFR 1.56, 1.97, 1.98**

Honorable Commissioner of Patents and Trademarks  
Washington, D. C. 20231

Sir:

Applicants submit herewith form PTO-1449, listing patents, publications, or other information of which they are aware which they believe may be material to patentability pursuant to 37 CFR 1.56(b), and in respect of which there may be a duty to disclose under 37 CFR 1.56(a), together with legible copies of the patents, publications, or other information listed.

While the items submitted with this Information Disclosure Statement may be material to patentability pursuant to 37 CFR 1.56, in accordance with 37 CFR 1.97(h) it shall not be construed to be an admission that any patent, publication, or other information cited is "prior art" or is material to patentability for this invention unless specifically designated as such. In accordance with 37 CFR 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other information material to patentability, as defined in 37 CFR 1.56(b), exists.

This Information Disclosure Statement is being filed with the filing of this application. Accordingly, it is not believed that any fee is required relating to the filing of this Information Disclosure Statement. If this is not the case, the Patent Office is hereby authorized to charge any related fee to Deposit Account No. 09-0456.

Respectfully submitted,

Date: 11/06/03

By: Robert A. Walsh

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**INFORMATION DISCLOSURE CITATION**  
*(Use several sheets if necessary)*

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## Group Art Unit

## U.S. PATENT DOCUMENTS

## FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
	GB2342722A	2000/04/19	United Kingdom			✓	

**OTHER DOCUMENTS** *(Including Author, Title, Date, Pertinent Pages, Etc.)*

	'Special Test Chip For Testing IC Tester', IBM Technical Disclosure Bulletin, Vol. 28, No. 1, June 1985, pp. 221-222
	'N-Way Testpoint For Complex LSI Design', IBM Technical Disclosure Bulletin, Vol. 13, No. 10, March 1972, pp. 2937-2938

**EXAMINER** \_\_\_\_\_ **DATE CONSIDERED** \_\_\_\_\_

**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.